

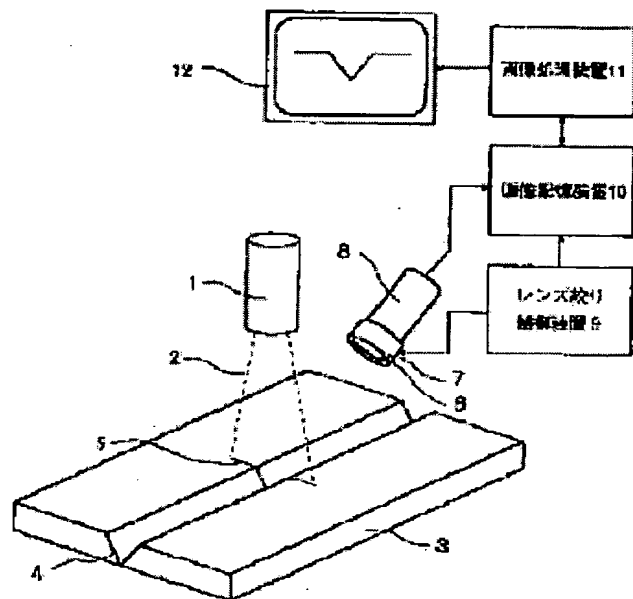
APPARATUS FOR MEASURING SECTIONAL SHAPE

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Abstract of JP9287926

PROBLEM TO BE SOLVED: To measure a sectional shape of an object highly accurately, by synthesizing optimum data for every part from a plurality of data obtained under different image pickup conditions, thereby obtaining a sectional image. **SOLUTION:** A cutting line 5 of a body 3 to be detected which is illuminated by a slit beam 2 is photographed by an imaging camera 8. The image is stored in an image memory Mn of an image memory device 10 with a photographed data number of $n=1$ and an aperture value of a lens 6 of S_n . Then, the number (n) is incremented by +1 and (n) pieces of photographed image data with aperture values $S_1 - S_n$ are stored in memories $M_1 - M_n$ until an input count of photographed image data is reached. Subsequently, a line number (i) in a longitudinal direction of the photographed image data is set to be 1 and a difference V_{ns} between an optimum luminance V_s and a maximum luminance V_n is initialized at a maximum value. The maximum luminance V_n of the number (i) in the memory Mn is obtained to calculate $V_n - V_s$. A minimum calculated value is set as an absolute value V_{ns} , and a photographed data number having data of the maximum luminance among the number (i) is selected. After the process, data of the number (i) is copied from the memory M_j to a memory M_0 , and the number (i) is incremented by +1. When all the lines are processed at an image processing unit 11, data photographed under an optimum aperture condition are synthesized for every line on the memory M_0 .



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